

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/676,174	KRTOLICA ET AL.
	Examiner	Art Unit
	Ellen C. Tran	2134

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	2/17/2007	ECT
NPL - IEEE/XPLORE	2/17/2007	ECT
INVENTOR SEARCH - PALM	2/17/2007	ECT
All claims were reviewed for 101 rejection	2/17/2007	ECT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner